

Search Notes

Application/Control No.

10/727,190

Examiner

Benjamin P. Geib

Applicant(s)/Patent under
Reexamination

PARK, HEONCHUL

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
712	228	3/29/2007	BPG

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated East Search	3/29/2007	BPG
Updated NPL Search (IEEE Xplore and Google Scholar)	3/29/2007	BPG